# FTE10N06NA

# N-Channel MOSFET

## **Applications:**

- Adaptor
- Charger
- .SMPS

# Lead Free Package and Finish

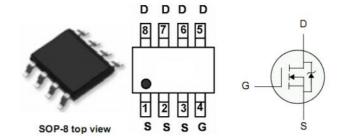
V <sub>DSS</sub>	R <sub>DS(ON)</sub> (Typ.)	I <sub>D</sub>
60V	8mΩ	55A

### Features:

- RoHS Compliant
- Low ON Resistance
- Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves

**Ordering Information** 

PART NUMBER		PACKAGE	BRAND
	FTE10N06NA	SOP-8	IPS



# **Absolute Maximum Ratings** $T_C=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	FTE10N06NA	Units
$V_{DSS}$	Drain-to-Source Voltage	60	V
I <sub>D</sub>	Continuous Drain Current	55	А
	Continuous Drain Current T <sub>C</sub> =100 ℃	8	А
I <sub>DM</sub>	Pulsed Drain Current, V <sub>GS</sub> @10V	32	А
Ъ	Power Dissipation	2.5	W
$P_D$	Derating Factor above 25 <sup>°</sup> C	0.02	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy	320	mJ
TL	Maximum Temperature for Soldering	300	
T <sub>J</sub> and T <sub>STG</sub>	Operating Junction and Storage	FF to 150	$^{\circ}$
	Temperature Range	-55 to150	

#### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units	Test Conditions
$R_{\theta JA}$	Junction-to-Ambient		50	°C/W	1 cubic foot chamber, free air.



## **OFF Characteristics** $T_C=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS}$ =0V, $I_D$ =250 $\mu$ A
^ D) / _ / ^ T	Breakdown Voltage Temperature		0.71		V/°C	Reference to 25℃,
$\triangle BV_{DSS}/\triangle T_{J}$	Coefficient,		0.71		V/C	I <sub>D</sub> =250μA
	Duain to Course I calcage Comment			1		$V_{DS}$ =60V, $V_{GS}$ =0V
						T <sub>J</sub> =25 ℃
I <sub>DSS</sub>	Drain-to-Source Leakage Current			100	μA	$V_{DS}$ =48V, $V_{GS}$ =0V
				100		T <sub>J</sub> =125℃
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			+100	nΛ	V <sub>GS</sub> =+20V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

# ON Characteristics T<sub>J</sub>=25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
R <sub>DS(ON)</sub>	Static Drain-to-Source On-Resistance		8	10	mΩ	$V_{GS}$ =10V, $I_D$ =4.8A (NOTE *4)
$V_{GS(TH)}$	Gate Threshold Voltage	1		3	V	$V_{DS}=V_{GS}$ , $I_{D}=250uA$
<b>9</b> fs	Forward Transconductance		65		S	$V_{DS}$ =15V, $I_{D}$ =8A (NOTE *4)

#### **Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Ма	Units	Test Conditions
				x.		
C <sub>iss</sub>	Input Capacitance		4050			\/ 0\/\/ 2E\/
C <sub>oss</sub>	Output Capacitance		280		pF	$V_{GS}$ = 0V, $V_{DS}$ = 25V f =1.0MHz
C <sub>rss</sub>	Reverse Transfer Capacitance		180			
Q <sub>g</sub>	Total Gate Charge		57			1 04 1/ 001/
$Q_{gs}$	Gate-to-Source Charge		16		nC	$I_D=8A, V_{DD}=30V$ $V_{GS}=10V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		13		]	

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Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
t <sub>d(ON)</sub>	Turn-on Delay Time		21			
t <sub>rise</sub>	Rise Time		27			$V_{DD}$ =30V, $I_D$ =4A,
t <sub>d(OFF)</sub>	Turn-Off Delay Time		63		ns	$V_G$ =10V $R_G$ =9.1 $\Omega$
t <sub>fall</sub>	Fall Time		30			





## Source-Drain Diode Characteristics Tc=25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
1	Continuous Source Current			0	^	
IS	(Body Diode)			8	Α	T 25°
1	Maximum Pulsed Current			22	^	T <sub>C</sub> =25°C
I <sub>SM</sub>	(Body Diode)			32	A	
V <sub>SD</sub>	Diode Forward Voltage			1.5	V	I <sub>SD</sub> =8A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time		42	45	ns	I <sub>S</sub> =8A,
Q <sub>rr</sub>	Reverse Recovery Charge		85	91	nC	di/dt=100A/us

#### Notes:

<sup>\*1.</sup>  $T_J = +25^{\circ}\mathbb{C}$  to  $+150^{\circ}\mathbb{C}$ .

<sup>\*2.</sup> Repetitive rating; pulse width limited by maximum junction temperature.

<sup>\*3.</sup> di/dt < 100 A/ $\mu$ s,  $V_{DD}$  < B $V_{DSS}$ ,  $T_J$ =+150  $^{\circ}$ C.

<sup>\*4.</sup> Pulse width < 380µs; duty cycle < 2%.

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